## CRYSTALLIZATION FEATURES OF AMORPHOUS FILMS OF Sb<sub>2</sub>S<sub>3</sub> Bagmut O.G., Bagmut I.O., Resnik M.O. National Technical University "Kharkiv Polytechnic Institute", Kharkiv

"In situ" electron beam irradiation is a spatially selective heating method which offers an opportunity to fabricate crystalline architectures in amorphous films under controlled conditions. In this work crystallization of amorphous films of Sb<sub>2</sub>S<sub>3</sub> of both stoichiometric composition and with the excess of Sb was studied by the methods of transmission electron microscopy with video registration of structural changes. Irradiation of amorphous film of Sb<sub>2</sub>S<sub>3</sub> with stoichiometric composition causes phase transformation, that occurs according to the scheme of layer polymorphous crystallization. A single flat ellipse-shaped crystal of Sb<sub>2</sub>S<sub>3</sub> nucleates and grows in the film region under investigation. The dependence on time of the length of major and minor ellipse axis of this crystal has a linear character. As the ellipse-shaped crystal grows, its eccentricity decreases exponentially with time. The dependence on time of the fraction crystallized x at layer polymorphous crystallization has a quadratic character (Fig 1a). Wherein the relative length  $\delta_0 \approx 4992$  [1].

Electron beam irradiation of amorphous non-stoichiometric films with excess of antimony initiates the predominant crystallization of Sb during the first stage of the process, and subsequent matrix Sb<sub>2</sub>S<sub>3</sub> crystallization during the second stage. As the film warms up, the density *n* and average value of the diameter  $\langle D \rangle$  of antimony particles monotonically increases and at saturation  $n \approx 7.5 \cdot 10^9$  cm<sup>-2</sup> and  $\langle D \rangle \approx 0.029$ µm. Then in the amorphous matrix with inclusions of micro-crystals of Sb a single flat ellipse-shaped crystal of Sb<sub>2</sub>S<sub>3</sub> was growing. The dependence on time of the fraction crystallized *x* at secondary polymorphous crystallization of Sb<sub>2</sub>S<sub>3</sub> described by a power function with the exponent of 0.68. Wherein the relative length  $\delta_0 \approx 9725$ .



FIG. 1. Time dependence of the fraction crystallized for polymorphous (a) and for secondary (b) crystallization of amorphous films of Sb<sub>2</sub>S<sub>3</sub>

[1] A.G. Bagmut, Functional Materials, 2019, vol. 26, 6-15.